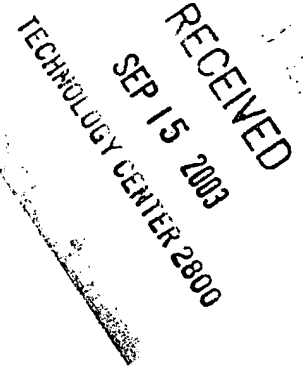




IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Zaidi
Serial No.: 09/967,176
Filed: September 28, 2001
For: Method for Overlay Metrology of Low Contrast Features

Docket No.: 01 P 15946 US
Art Unit: 2877
Examiner: Gordon J. Stock Jr.



Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Transmittal of Substitute Specification under 37 CFR 1.125(a)

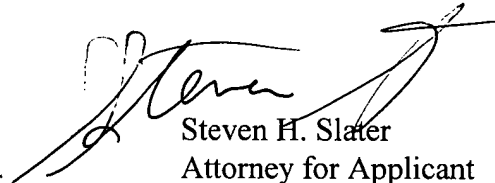
Dear Sir:

Enclosed herewith in response to Examiner's request for a substitute specification is a duplicate of the substitute specification filed January 17, 2002 along with a copy of the return receipt postcard acknowledging receipt of the same.

No new matter has been added and no matter has been deleted, hence, a marked-up copy of the specification is not required.

Please contact Applicant's attorney with any questions regarding this matter.

Respectfully submitted,


Steven H. Slater
Attorney for Applicant
Reg. No. 35,361

Slater & Matsil, L.L.P.
17950 Preston Rd., Suite 1000
Dallas, TX 75252
Tel: 972-732-1001
Fax: 972-732-9218

The stamp of the USPTO, placed hereon, acknowledges receipt of:

Applicant: S. Zaidi

Attorney Docket: 01 P 15946 US

Serial No: 09/967,176

Art Unit: TBD

Date Filed: 09/28/2001

Date Mailed: November 9, 2001



Received By:
Blair & Matcill

JAN 28 2002

- Transmittal Form (1 page)
- Response to Notice to File Corrected Application Papers (1 page)
- Notice to File Corrected Application Papers (1 page)
- ~~Complete Copy of Substitute Specification (23 pages)~~
- Information Disclosure Statement Transmittal (1 page)
- Information Disclosure Statement By Applicant (1 page)
- Three (3) References
- Return Postcard (2)



Pam Gewirtz
Infineon Technologies North America
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Iselin, NJ 08830



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